

<b>VDS</b>	<b>RDS(on)</b>	<b>ID@25°C</b>
1200V	40mΩ	67A

**Applications:**

- Renewable Energy
- Switch Mode Power Supplies
- EV Battery Chargers
- High voltage DC-DC converters

**Features:**

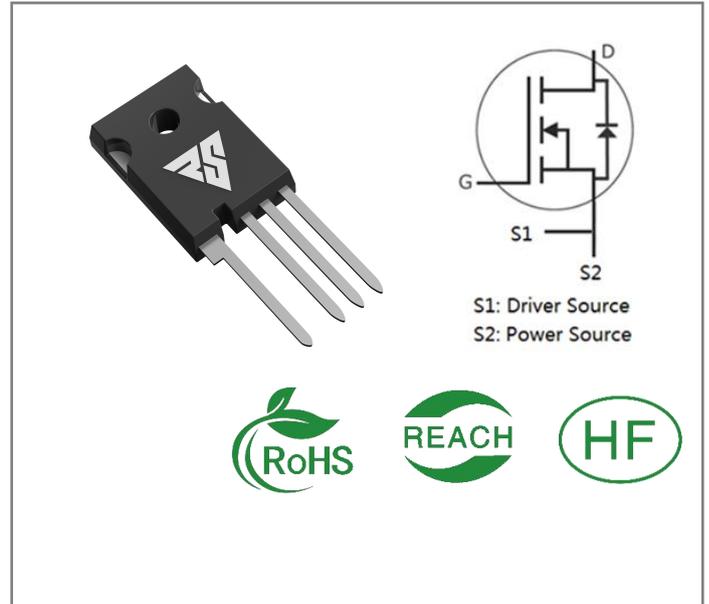
- High Blocking Voltage with Low On-Resistance
- High Speed Switching with Low Capacitances
- Easy to Parallel and Simple to Drive

**Benefits:**

- HigherSystemEfficiency
- ReducedCoolingRequirements
- IncreasedPowerDensity
- IncreasedSystemSwitchingFrequency

**Ordering Information**

Part Number	Package	Marking	Packing	Qty.
RSM12H040Z	TO-247-4	RSM12H040Z	Tube	30 PCS


**Maximum Ratings** (T<sub>J</sub>= 25°C unless otherwise specified)

Symbol	Parameter	Value	Unit	Test Conditions	Note
VDSmax	Drain - Source Voltage	1200	V	VGS=0V, ID =100μA	
VGSmax	Gate - Source Voltage	-10/+23	V	Absolute maximum values	
VGSop	Gate - Source Voltage	-5/+18	V	Recommended operational values	
ID	Continuous Drain Current	67 47	A	VGS=18V, TC =25°C VGS=18V, TC =100°C	
ID(pulse)	Pulsed Drain Current	201	A	Pulse width tp limited by TJmax	
PD	Power Dissipation	375	W	TC =25°C, Tj =175°C	
TL	Solder Temperature, 1.6mm from case for 10s	260	°C		
TJ, Tstg	Operating Junction and Storage Temperature	-55 to + 175	°C		
Md	Mounting Torque, (M3 or 6-32 screw)	1 8.8	Nm lbf-in		

**Electrical Characteristics** (T<sub>J</sub>= 25°C unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
V(BR) DSS	Drain-Source Breakdown Voltage	1200			V	V <sub>GS</sub> =0V, I <sub>D</sub> =100μA
VGS(th)	Gate Threshold Voltage	2.0	2.8	4.0	V	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> =9.2mA
			2.0		V	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> =9.2mA, T <sub>J</sub> =175°C
IDSS	Zero Gate Voltage Drain Current		1	100	μA	V <sub>DS</sub> = 1200V, V <sub>GS</sub> =0V
IGSS	Gate-Source Leakage Current		10	100	nA	V <sub>GS</sub> =23V, V <sub>DS</sub> = 0V
			-10	-100	nA	V <sub>GS</sub> =-10V, V <sub>DS</sub> = 0V
RDS(on)	Drain-Source on-state Resistance		40	52	mΩ	V <sub>GS</sub> =18V, I <sub>D</sub> =33.3A
			60			V <sub>GS</sub> =18V, I <sub>D</sub> =33.3A, T <sub>J</sub> =175°C
Gfs	Forward transconductance		21		S	V <sub>DS</sub> =20V, I <sub>D</sub> =33.3A
			20.5			V <sub>DS</sub> =20V, I <sub>D</sub> =33.3A, T <sub>J</sub> =175°C
Ciss	Input Capacitance		2320		pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =1000 V f=1MHz, V <sub>AC</sub> =25 mV
Coss	Output Capacitance		89			
Crss	Reverse Transfer Capacitance		8			
Eoss	Stored Energy inOutputCapacitance		45		μJ	V <sub>DS</sub> =800V, V <sub>GS</sub> =-5/18V I <sub>D</sub> = 30A, R <sub>G(ext)</sub> = 2.5Ω L= 100μH
EON	Turn-On Switching Energy		600			
EOFF	Turn-Off Energy		60			
td(on)	Turn-On Delay Time		14		ns	V <sub>DS</sub> =800V, V <sub>GS</sub> =-5/18V I <sub>D</sub> = 33.3A, R <sub>G(ext)</sub> = 2.5Ω R <sub>L</sub> =24Ω
tr	Rise Time		19			
td(off)	Turn-Off Delay Time		28			
tf	Fall Time		7.4			
RG	Internal Gate Resistance		3.1		Ω	f=1 MHz, V <sub>AC</sub> =25MV
Qgs	Gate to Source Charge		32		nC	V <sub>DS</sub> =800V V <sub>GS</sub> =-5/18V I <sub>D</sub> =33.3A
Qgd	Gate to Drain Charge		20			
Qg	Total Gate Charge		108			

**Reverse Diode Characteristics** (T<sub>J</sub>= 25°C unless otherwise specified)

Symbol	Parameter	Typ.	Max	Unit	Test Conditions
VSD	Diode Forward Voltage	4.2		V	V <sub>GS</sub> =-5V, I <sub>SD</sub> = 16.5A, T <sub>J</sub> = 25°C
		3.6		V	V <sub>GS</sub> =-5V, I <sub>SD</sub> = 16.5A, T <sub>J</sub> = 175°C
I <sub>S</sub>	Continuous Diode Forward Current		67	A	TC= 25°C
trr	Reverse Recovery time	23		ns	VR = 800V I <sub>SD</sub> =33.3A
Q <sub>rr</sub>	Reverse Recovery Charge	279		nC	
I <sub>rrm</sub>	Peak Reverse Recovery Current	16		A	

**Thermal Characteristics** (T<sub>J</sub>= 25°C unless otherwise specified)

Symbol	Parameter	Typ.	Max	Unit	Test Conditions
R <sub>θJC</sub>	Thermal Resistance from Junction to Case	0.40		°C/W	
R <sub>θJA</sub>	Thermal Resistance From Junction to Ambient		40		

Typical Feature Curve

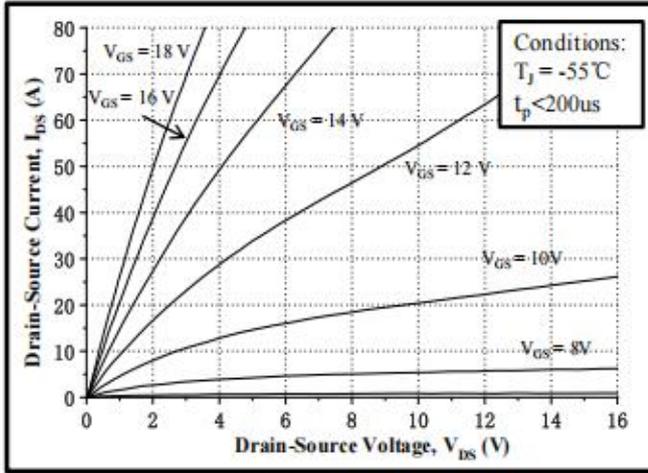


Figure 1. Output Characteristics  $T_J = -55^\circ\text{C}$

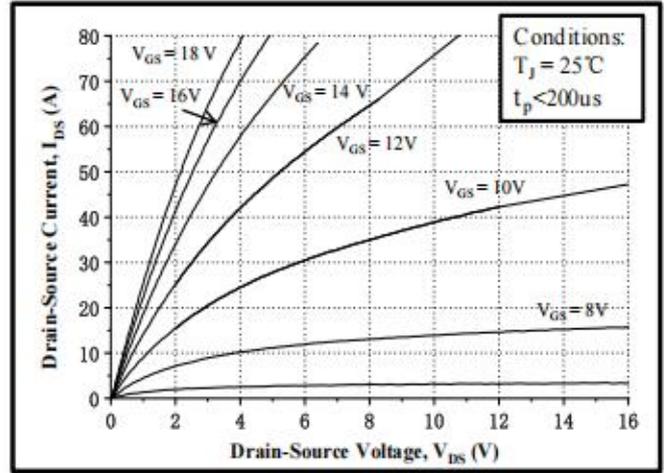


Figure 2. Output Characteristics  $T_J = 25^\circ\text{C}$

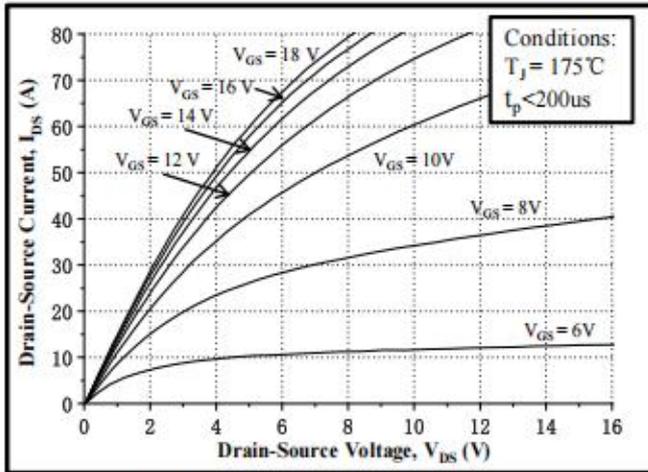


Figure 3. Output Characteristics  $T_J = 175^\circ\text{C}$

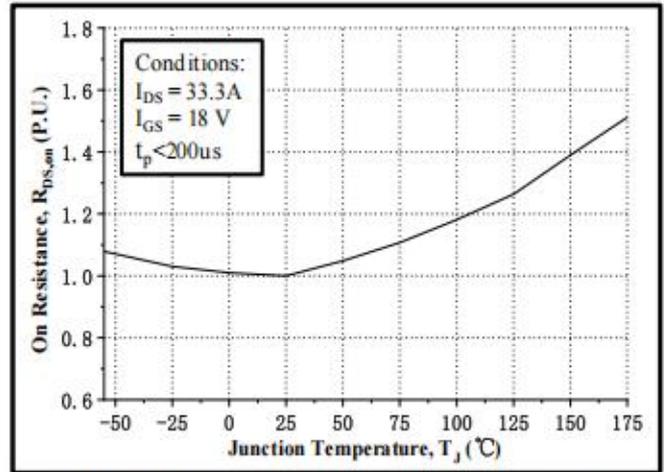


Figure 4. Normalized On-Resistance vs. Temperature

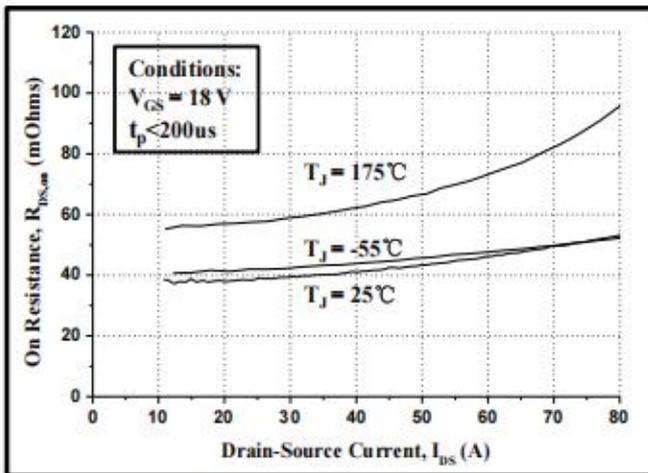


Figure 5. On-Resistance vs. Drain Current  
For Various Temperatures

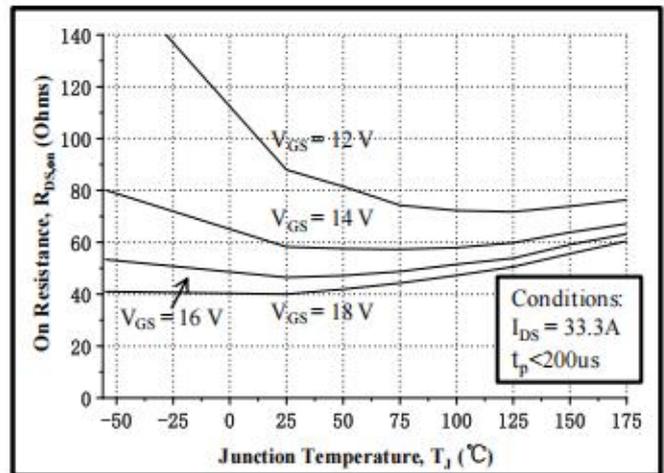


Figure 6. On-Resistance vs. Temperature  
For Various Gate Voltage

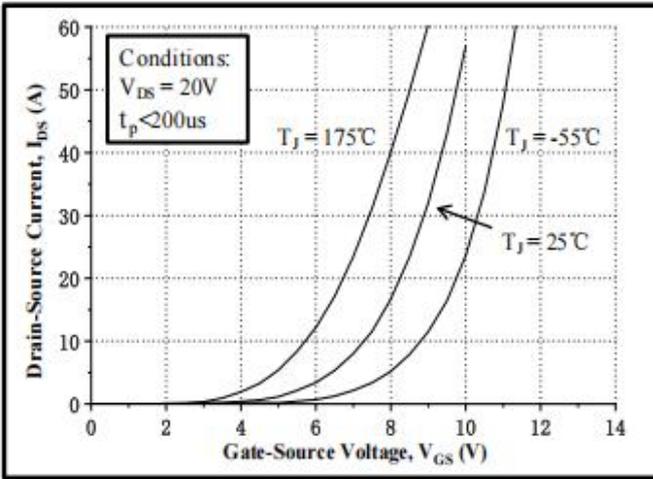


Figure 7. Transfer Characteristic for Various Junction Temperatures

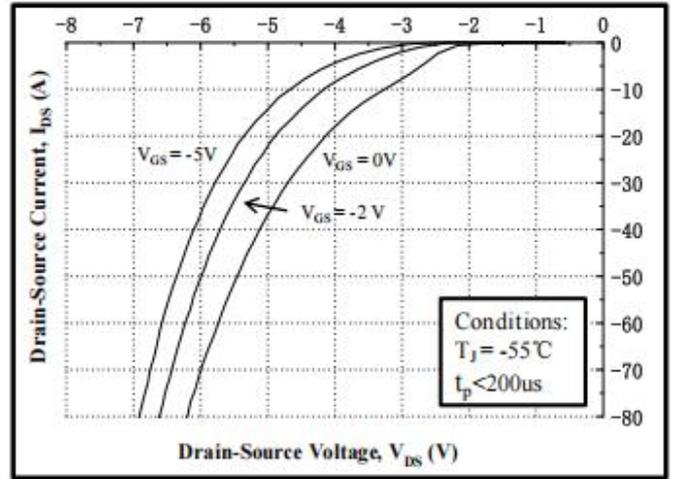


Figure 8. Body Diode Characteristic at -55°C

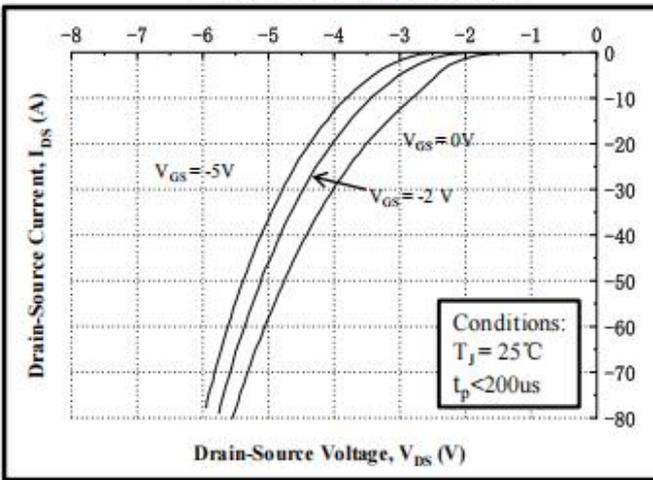


Figure 9. Body Diode Characteristic at 25°C

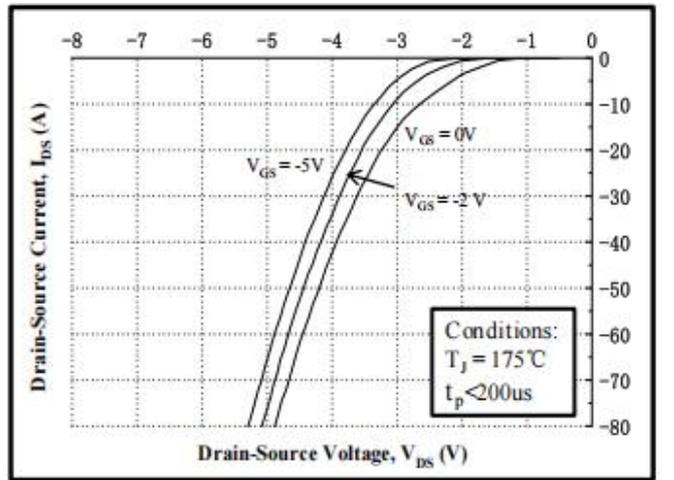


Figure 10. Body Diode Characteristic at 175°C

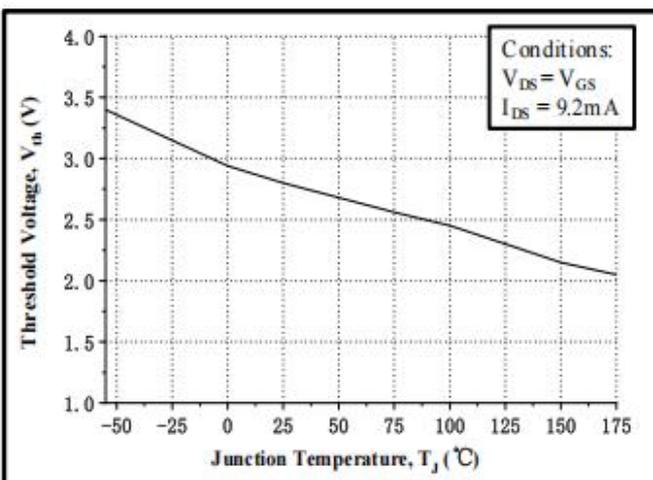


Figure 11. Threshold Voltage vs. Temperature

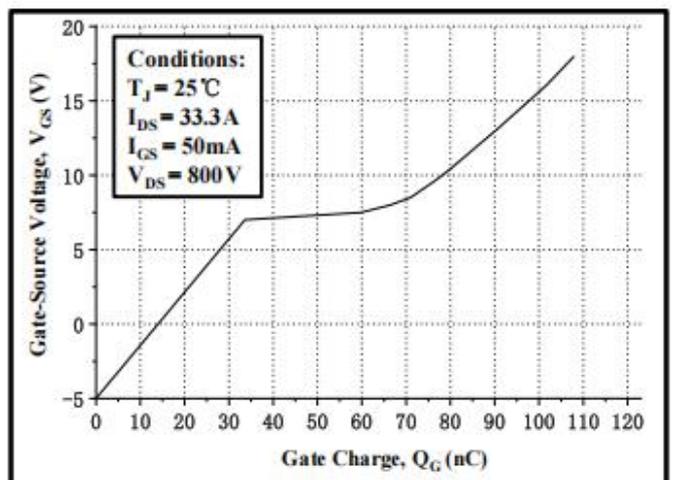


Figure 12. Gate Charge Characteristics

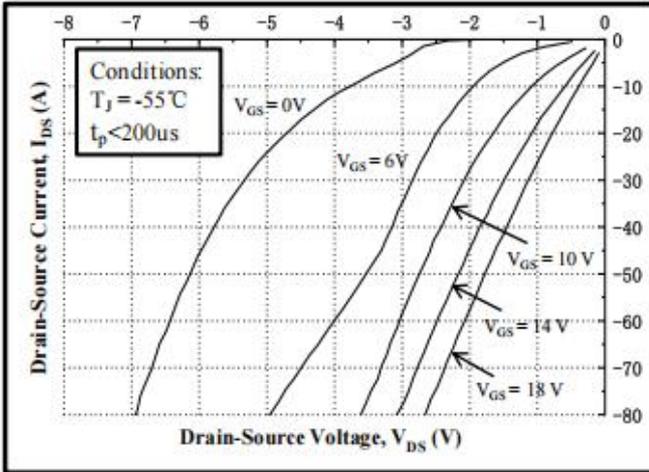


Figure 13. 3rd Quadrant Characteristic at -55°C

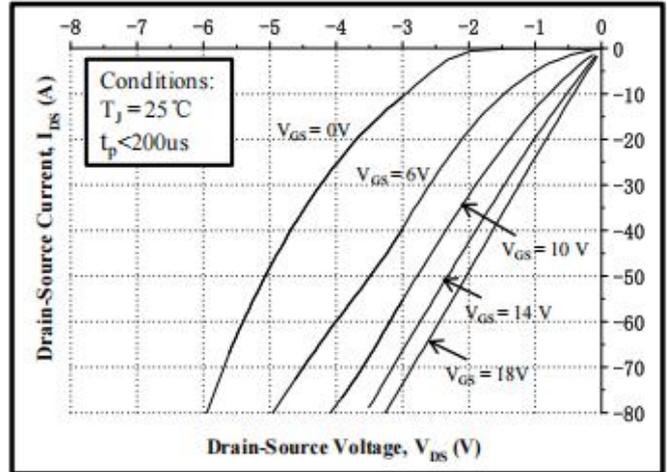


Figure 14. 3rd Quadrant Characteristic at 25°C

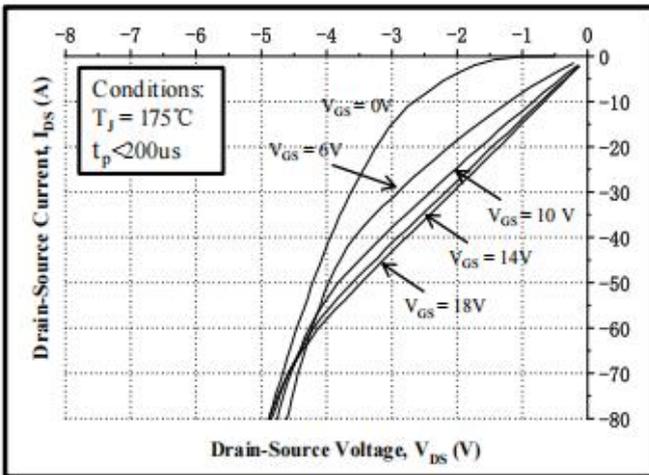


Figure 15. 3rd Quadrant Characteristic at 175 °C

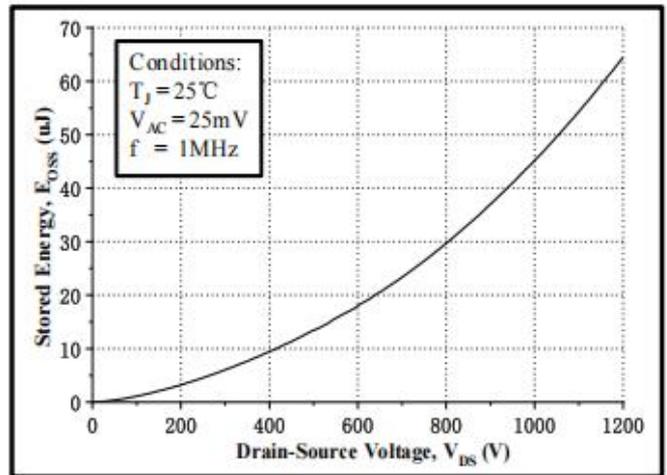


Figure 16. Output Capacitor Stored Energy

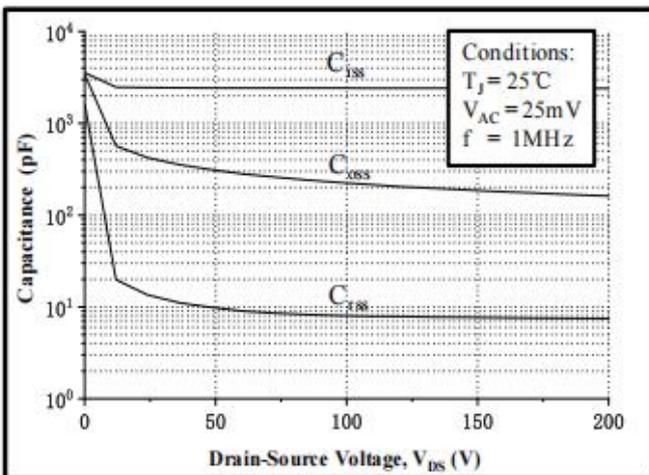


Figure 17. Capacitances vs. Drain-Source Voltage (0 - 200V)

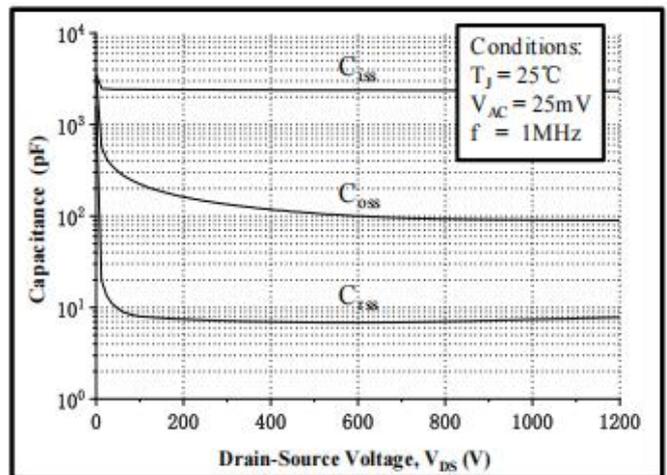


Figure 18. Capacitances vs. Drain-Source Voltage (0 - 1200V)

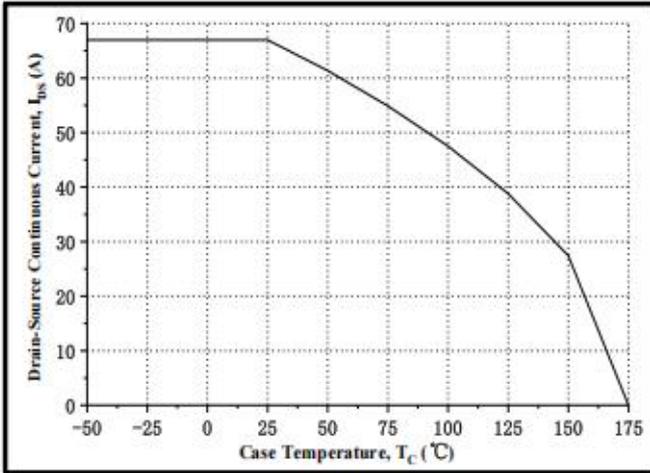


Figure 19. Continuous Drain Current Derating vs. Case Temperature

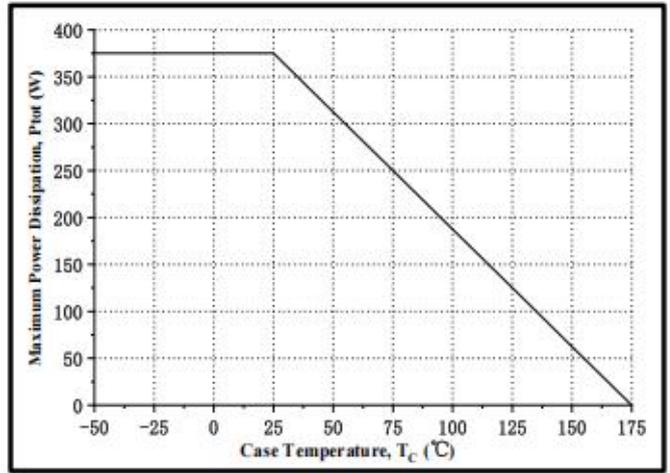


Figure 20. Maximum Power Dissipation Derating vs. Case Temperature

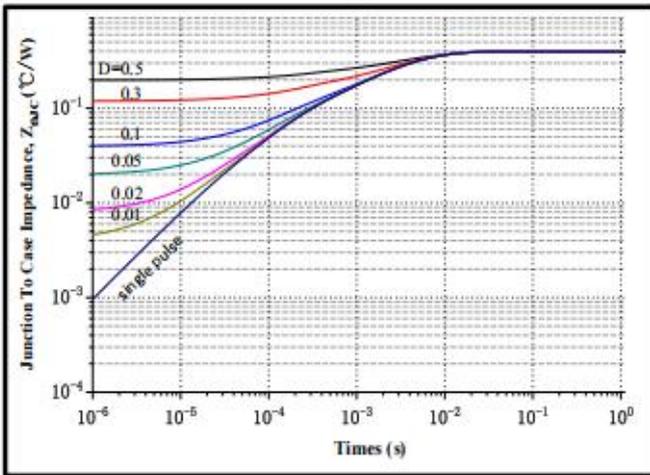


Figure 21. Transient Thermal Impedance (Junction - Case)

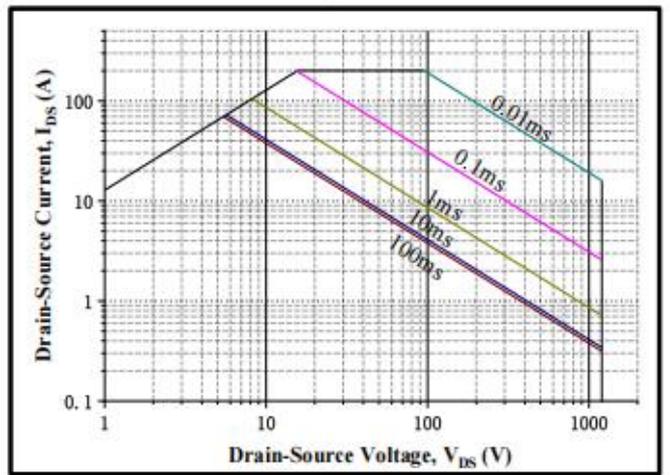


Figure 22. Safe Operating Area

Test Circuit Schematic

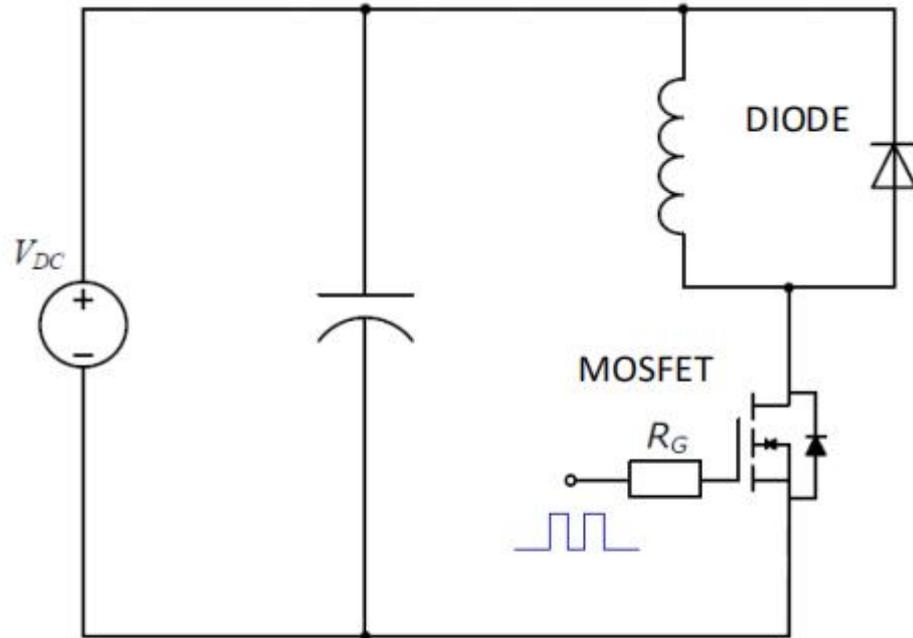
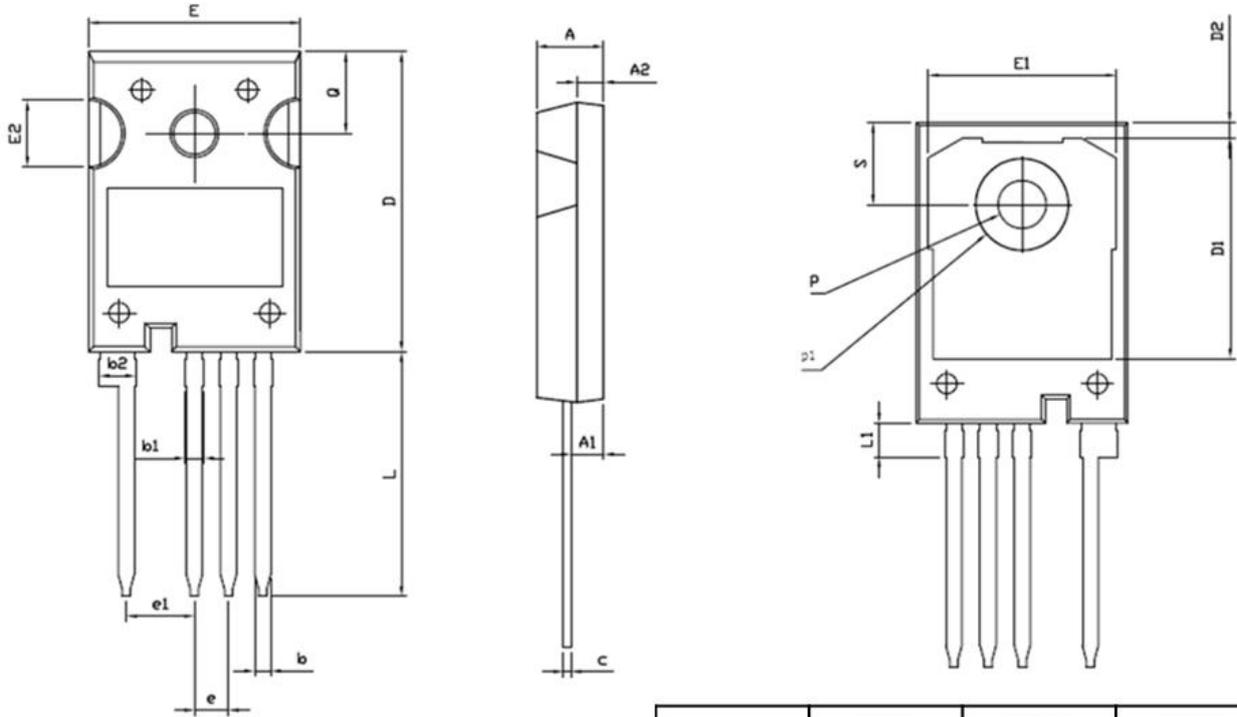
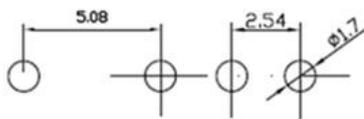


Figure 23. Clamped Inductive Switching  
Waveform Test Circuit

Package outline drawing(TO-247-4 Unit: mm)



RECOMMENDED LAND PATTERN



UNIT: mm

	MIN	NOM	MAX
A	4.80	5.00	5.20
A1	2.25	2.40	2.55
A2	1.85	2.00	2.15
b	1.05	1.20	1.35
b1	1.00	1.30	1.60
b2	2.35	2.65	2.95
c	0.50	0.60	0.70
D	22.29	22.54	22.79
D1	16.00	16.50	17.00
D2	0.97	1.17	1.37
e	2.34	2.54	2.74
e1	4.88	5.08	5.28
E	15.60	15.80	16.00
E1	13.50	14.00	14.50
E2	4.80	5.00	5.20
L	18.08	18.38	18.68
L1	2.38	2.58	2.78
p	3.50	3.60	3.70
p1	6.60	7.10	7.60
Q	6.00	6.15	6.30
S	6.00	6.15	6.30

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